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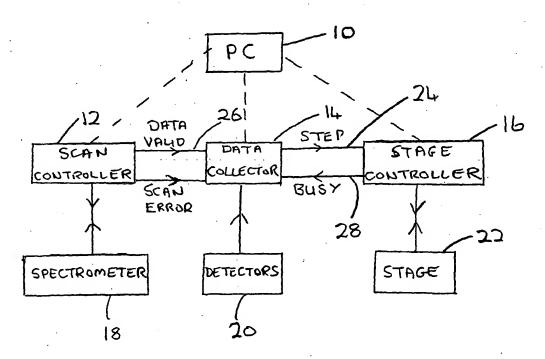
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(54) Title: SYSTEM AND METHOD FOR SCANNING IR MICROSCOPY



(57) Abstract: An FT-IR microscope is operated in association with a scanning spectrometer in such a way that incremental movement of the movable stage of the microscope is synchronised with the scanning spectrometer. This minimises delays in processing time.